

1149.1/JTAG Pod Offers Non-volatile Test Program and Failure Memory



Designed to allow plug-and-play test and FPGA configuration without a computer, cable, or software, Intellitech's UltraTAP-BT Bluetooth-enabled IEEE 1149.1/JTAG pod comes with non-volatile test program and failure memory. 1149.1/JTAG-based tests occur via the UltraTAP-BT Flash memory at a continuous test clock rate of up to 50 MHz, and test flow, test scripts, and third-party Serial Vector Format files download over a USB connection to the pod using Intellitech's Eclipse software. Test sequences are executed at power-up via pushbutton or Bluetooth commands, and pass and fail LEDs indicate the status of the test. A burst of compressed failure information is sent so that the computer can diagnose the failure to a net, pin, or register fault description, and failure information is stored in non-volatile memory for later retrieval via USB or Bluetooth if a Bluetooth connection is not found. Several pods can be used at once, each containing different test programs targeted for different PCB types.

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[1] <http://www.intellitech.com/>